



PRODUCT BULLETIN
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ISSUE DATE: 13-Aug-2013
NOTIFICATION: 15793
TITLE: 9S08RD16/8,9S08RE16/8,HC908LJ12, etc KES-CHINA FINAL TEST SITE EXPANSION
EFFECTIVE DATE: 14-Aug-2013

DEVICE(S)

MPN
MC908GP32CPE
MC908GR4CDWE
MC908GR8ACDWE
MC908GR8CDWE
MC908GR8CDWER
MC908JL16CSPE
MC908JL3ECFAE
MC908LJ12CFBE
MC908LJ12CPBE
MC908LJ12CPBER
MC908LJ24CPBE
MC908LJ24CPBER
MC908LK24CPBE
MC9RS08KA1CDB
MC9RS08KA1CDBR
MC9RS08KA2CDB
MC9S08AC16CBE
MC9S08AC16MBE
MC9S08AC8MBE
MC9S08LH36CLH
MC9S08LH36CLK
MC9S08LH64CLH
MC9S08LH64CLK
MC9S08LL36CLH
MC9S08LL36CLK
MC9S08LL64CLH

MC9S08LL64CLK
MC9S08RD16CDWE
MC9S08RD16DWE
MC9S08RE16CFJE
MC9S08RE16FJE
MC9S08RE8CFJE
MC9S08RE8CFJER
MC9S08RE8FJE
MC9S08SH4CFK
MC9S08SH4MFK
MC9S08SH8CFK
MC9S08SH8MFK

AFFECTED CHANGE CATEGORIES

- SUBCONTRACTOR TEST SITE

DESCRIPTION OF CHANGE

Freescale Semiconductor is announcing the Final Test site capacity expansion for the products listed in this notice, these products are currently being Final Tested in Freescale FSL-TJN-FM, Tianjin, China and have been qualified in KES-CHINA, Tianjin, China as an additional Final Test site.

REASON FOR CHANGE

Qualification of the KES-CHINA, Tianjin, China, Final Test Facility to improve manufacturing flexibility and customer support.

ANTICIPATED IMPACT OF PRODUCT CHANGE(FORM, FIT, FUNCTION, OR RELIABILITY)

There is no impact on device form, fit, function or reliability. The equivalent final test flows, hardware and software currently used in FSL-TJN-FM, Tianjin, China Final Test facility will be implemented at the KES-CHINA, Tianjin, China Final Test facility.

NOTE:

THE CHANGE(S) SPECIFIED IN THIS NOTIFICATION WILL BE IMPLEMENTED ON THE

EFFECTIVE DATE LISTED ABOVE. To request further data or inquire about the notification, please enter a [Service Request](#)

For sample inquiries - please go to www.freescale.com

QUAL DATA AVAILABILITY DATE: 24-Jul-2013

QUALIFICATION STATUS: COMPLETED

QUALIFICATION PLAN:

Freescale Semiconductor Manufacturing standard specification for test transfers was followed for the Test expansion.

RELIABILITY DATA SUMMARY:

This device is fully qualified. No further Reliability data is needed for this change.

ELECTRICAL CHARACTERISTIC SUMMARY:

Parametric comparison between FSL-TJN-FM, Tianjin, China and KES-CHINA, Tianjin, China was completed. Parameters show no significant difference.

CHANGED PART IDENTIFICATION:

There no change to the orderable part number.

ATTACHMENT(S):

External attachment(s) FOR this notification can be viewed AT:
[15793 Qualfication Report-Test Site Expansion.pdf](#)
